March 1987

DM85S06 Open-Collector DM75S07/DM85S07 TRI-STATE® DM75S07A/DM85S07A High Speed TRI-STATE Non-Inverting, 64-Bit (16 x 4) RAMs

General Description

These 64-bit active-element memories are monolithic Schottky-clamped transistor-transistor logic (TTL) arrays organized as 16 words of 4 bits each. They are fully decoded and feature a chip-enable input to simplify decoding required to achieve the desired system organization. The memories feature PNP input transistors that reduce the low level input current requirement to a maximum of -0.25 mA, only one-eighth that of a DM54S/DM74S standard load factor. The chip-enable circuitry is implemented with minimal delay times to compensate for added system decoding.

The TRI-STATE output combines the convenience of an open-collector with the speed of a totem-pole output; it can be bus-connected to other similar outputs; yet it retains the fast rise time characteristics of the TTL totem-pole output. Systems utilizing data bus lines with a defined pull-up impedance can employ the open-collector DM85S06.

Write Cycle: The information at the data input is written into the selected location when both the chip-enable input and the read/write input are low. While the read/write input is low, the outputs are in the high-impedance state. When a number of the DM85S07 outputs are bus-connected, this high-impedance state will neither load nor drive the bus line, but it will allow the bus line to be driven by another active output or a passive pull-up if desired.

Read Cycle: The stored information is available at the outputs when the read/write input is high and the chip-enable

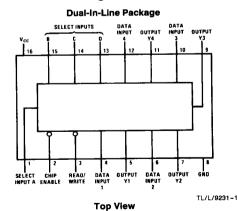
is low. When the chip-enable is high, the outputs will be in the high-impedance state.

The fast access time of the DM75S07A makes it particularly attractive for implementing high-performance memory functions requiring access times less than 25 ns. The high capacitive drive capability of the outputs permits expansion without additional output buffering. The unique functional capability of the DM75S07 outputs being at a high-impedance during writing, combined with the data inputs being inhibited during reading, means that both data inputs and outputs can be connected to the data lines of a bus-organized system without the need for interface circuits.

Features

- Schottky-clamped for high speed applications (75S07A)
 Access from chip-enable input
 17 ns max
 Access from address inputs
 25 ns max
- TRI-STATE outputs drive bus-organized systems and/or high capacitive loads
- DM85S06 is functionally equivalent and has open-collector outputs
- DM75SXX is guaranteed for operation over the full military temperature range of -55°C to +125°C
- Compatible with most TTL logic circuits
- Chip-enable input simplifies system decoding

Connection Diagram



Truth Table

	Inp	uts	
Function	Chip- Enable	Read/ Write	Output
Write	L	L	High-Impedance
Read	L	н	Stored Data
Inhibit	Н	Х	High-Impedance

H = High Level, L = Low Level, X = Don't Care

Order Number DM75S07J, DM75S07AJ, DM85S06J, DM85S07J, DM85S07AJ, DM85S06N, DM85S07N or DM85S07AN See NS Package Number J16A or N16E

Absolute Maximum Rat	Operating Conditions							
If Military/Aerospace specified de contact the National Semicondu Distributors for availability and spe	tor Sales Office/	Supply Voltage (V _{CC}) DM75S07(A)	Min 4.5	Max 5.5	Units V			
Supply Voltage, V _{CC}	7.0V	DM85S06/DM85S07(A)	4.75	5.25	v			
Input Voltage	5.5V	Temperature (T _A) DM75S07(A)	-55	+ 125	°C			
Output Voltage	5.5V	DM85S06/DM85S07(A)	0	+70	č			
Storage Temperature Range	-65°C to +150°C	DIMI033007 DIMI03307 (A)	U	Ŧ 70				
Lead Temperature (Soldering, 10 sec.)	+ 300°C							

DM85S06, DM75S07/DM85S07, DM75S07A/DM85S07A Electrical Characteristics

over recommended operating free-air temperature range unless otherwise noted (Notes 2 and 3)

Symbol	Parameter	Co	nditions	Min	Тур	Max	Unit
V _{IH}	High Level Input Voltage			2			V
V _{IL}	Low Level Input Voltage					0.8	V
V _{OH}	High Level Output Voltage	V _{CC} = Min	$I_{OH} = -2.0 \text{ mA},$ DM75S07(A)	2.4	3.4		v
			$I_{OH} = -5.2 \text{ mA},$ DM85S07(A)	2.4	3.2		٧
ICEX	High Level Output Current	V _{CC} = Min	V _{OH} = 2.4V			40	μΑ
	Open-Collector Only		V _{OH} = 5.5V			100	μА
V _{OL}	Low Level Output	V _{CC} = Min	I _{OL} = 16 mA			0.45	V
	Voltage		I _{OL} = 20 mA			0.5	V
l _{iH}	High Level Input Current	V _{CC} = Max, V			10	μΑ	
l _l	High Level Input Current at Maximum Voltage	V _{CC} = Max, V _I = 5.5V				1.0	mA
I _{IL}	Low Level Input Current	V _{CC} = Max, V _I = 0.40V				-250	μΑ
los	Short Circuit Output Current (Note 4)		V _{CC} = Max, V _O = 0V DM75S07(A), DM85S07(A)			-90	mA
lcc	Supply Current (Note 5)	V _{CC} = Max			75	100	mA
V _{IC}	Input Clamp Voltage	V _{CC} = Min, I _I	= -18 mA			-1.2	mA
lozh	TRI-STATE Output Current, High Level Voltage Applied	V _{CC} = Max, V DM75S07(A),	•			40	μΑ
lozL	TRI-STATE Output Current, Low Level Voltage Applied	V _{CC} = Max, V _O = 0.4V DM75S07(A), DM85S07(A)		-40			μΑ
C _{IN}	Input Capacitance	V _{CC} = 5V, V _{IN} = 2V, T _A = 25°C, 1 MHz			4		pF
co	Output Capacitance	V _{CC} = 5V, V _O = 2V, T _A = 25°C, 1 MHz Output "Off"			6		pF

<code>DM75S07/DM85S07</code> Switching Characteristics over recommended operating ranges of T_{A} and V_{CC} unless otherwise noted

		Conditions	DM75S07							
Symbol	Parameter		Min	Typ (Note 1)	Max	Min	Typ (Note 1)	Max	Units	
t _{AA}	Access Time from Addre	ess			25	50		25	35	ns
t _{CZH}	Output Enable Time to High Level	Access Times from			12	25		12	17	ns
^t CZL	Output Enable Time to Low Level	Chip-Enable	C _L = 30 pF, R _L = 280Ω (Figure 4)		12	25		12	17	ns
twzн	Output Enable Time to High Level	Sense Recovery Times			13	35		13	25	ns
t _{WZL}	Output Enable Time to Low Level	from Read/Write			13	35		13	25	ns
tcHZ	Output Disable Time from High Level	Disable Times from	C _L = 5 pF, R _L = 280Ω (Figure 4)		12	25		12	17	ns
tCLZ	Output Disable Time from Low Level	Chip-Enable			12	25		12	17	ns
twHZ	Output Disable Time from High Level	Disable Times from			15	35		15	25	ns
t _{WLZ}	Output Disable Time from Low Level	Read/Write			15	35		15	25	ns
t _{WP}	Width of Write Enable P	ulse (Read/Write Low)		25			25			ns
t _{ASW}	Set-Up Time (Figure 1)	Address to Read/Write		0			0			ns
tosw		Data to Read/Write		25			25			ns
tcsw		Chip-Enable to Read/Write		0			0			ns
t _{AHW}	Hold Time (Figure 1)	Address from Read/Write		0			0			ns
t _{DHW}		Data from Read/Write		0			0			ns
tchw		Chip-Enable from Read/Write		0			0			ns

<code>DM75S07A/DM85S07A</code> Switching Characteristics over recommended operating ranges of T_A and V_{CC} unless otherwise noted

		Conditions	DM75\$07A							
Symbol	Parameter		Min	Typ (Note 1)	Max	Min	Typ (Note 1)	Max	Units	
t _{AA}	Access Time from Addr	ess			20	30		20	25	ns
t _{CZH}	Output Enable Time to High Level	Access Times from			12	25		12	17	ns
^t CZL	Output Enable Time to Low Level	Chip-Enable	$C_L = 30 \text{ pF},$ $R_L = 280\Omega$		12	25		12	17	ns
twzн	Output Enable Time to High Level	Sense Recovery Times	(Figure 4)		13	35		13	25	ns
twzL	Output Enable Time to Low Level	from Read/Write			13	35		13	25	ns
^t CHZ	Output Disable Time from High Level	Disable Times from	$C_L = 5 pF,$ $R_L = 280\Omega$		12	25		12	17	ns
†CLZ	Output Disable Time from Low Level	Chip-Enable			12	25		12	17	ns
^t wHZ	Output Disable Time from High Level	Disable Times from	(Figure 4)		15	35		15	25	ns
t _{WLZ}	Output Disable Time from Low Level	Read/Write			15	35		15	25	ns
t _{WP}	Width of Write Enable P	ulse (Read/Write Low)		25			20			ns
tasw	Set-Up Time (Figure 1)	Address to Read/Write		0			0			ns
tosw		Data to Read/Write		25			20			ns
tcsw		Chip-Enable to Read/Write		0			0			ns
tahw	Hold Time (Figure 1)	Address from Read/Write		0			0			ns
t _{DHW}		Data from Read/Write		0			0			ns
tchw		Chip-Enable from Read/Write		0			0			ns

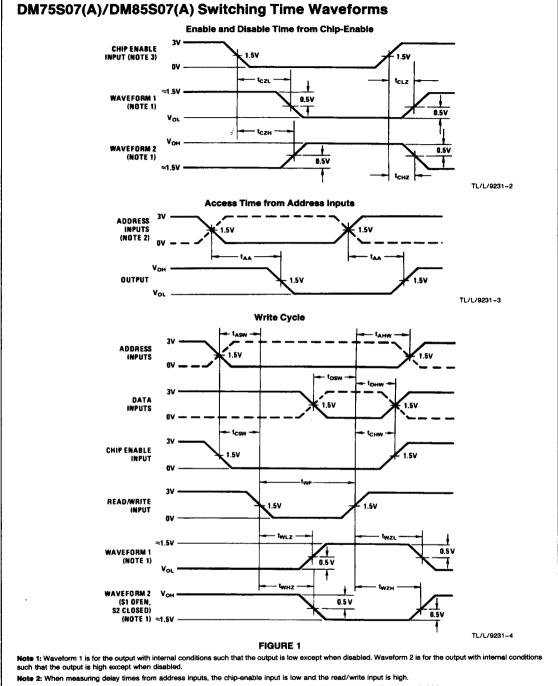
Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device

Note 2: Unless otherwise specified min/max limits apply across the -- 55°C to + 125°C temperature range for the DM75S07(A) and across the 0°C to + 70°C range for the DM85S07(A). All typicals are given for $V_{CC} = 5.0V$ and $T_A = 25^{\circ}C$.

Note 3: All currents into device pins shown as positive, out of device pins as negative, all voltages referenced to ground unless otherwise noted. All values shown as max or min on absolute value basis.

Note 4: Only one output at a time should be shorted.

Note 5: ICC is measured with all inputs grounded; and the outputs open.



Note 3: When measuring delay times from chip-enable input, the address inputs are steady-state and the read/write input is high.

Note 4: Input waveforms are supplied by pulse generators having the following characteristics: $t_f \le 2.5$ ns, $t_f \le 2.5$ ns, PRR ≤ 1 MHz and $Z_{OUT} = \approx 50\Omega$.

TL/L/9231-5

DM75S06/DM85S06 Switching Characteristics

over recommended operating ranges of TA and VCC unless otherwise noted

Symbol		Conditions	DM75S06			DM85S06				
	Parameter		Min	Typ (Note 1)	Max	Min	Typ (Note 1)	Max	Units	
taa	Access Times from Add	ress			25	50		25	35	ns
t _{CHL}	Enable Time from Chip-Enable		$C_{L} = 30 \text{ pF},$ $R_{L1} = 300\Omega,$ $R_{L2} = 600\Omega$ (Figure 4)		12	25		12	17	ns
twhL	Enable Time from Read/Write	Sense Recovery Time from Read/Write			13	35		13	25	ns
t _{CLH}	Disable Time from Chip-Enable				12	25		12	20	ns
twLH	Disable Time from Read/Write				13	35		13	25	ns
t _{WP}	Width of Write Enable Pulse (Read/Write Low)			25			25			ns
tasw	Set-Up Time (Figure 2)	Address to Read/Write		0			0			ns
tosw		Data to Read/Write		25			25			ns
tcsw		Chip-Enable to Read/Write		0			0			ns
tahw	Hold Time (Figure 2)	Address from Read/Write		0			0			ns
t _{DHW}		Data from Read/Write		0			0			ns
tCHW		Chip-Enable from Read/Write		0			0			ns

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

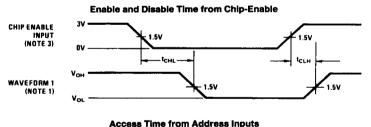
Note 2: Unless otherwise specified min/max limits apply across the -55° C to $+125^{\circ}$ C temperature range for the DM75S07(A) and across the 0° C to $+70^{\circ}$ C range for the DM85S07(A). All typicals are given for $V_{CC}=5.0V$ and $T_{A}=25^{\circ}$ C.

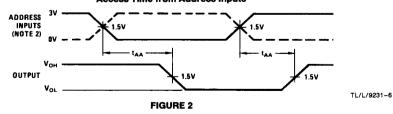
Note 3: All currents into device pins shown as positive, out of device pins as negative, all voltages referenced to ground unless otherwise noted. All values shown as max or min on absolute value basis.

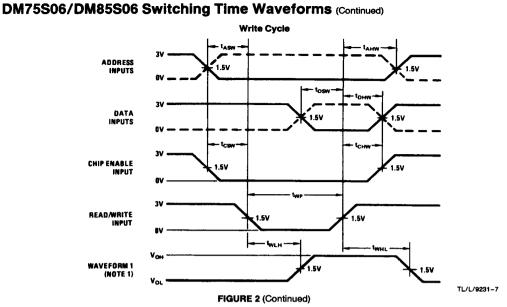
Note 4: Only one output at a time should be shorted.

Note 5: I_{CC} is measured with all inputs grounded; and the outputs open.

DM75S06/DM85S06 Switching Time Waveforms







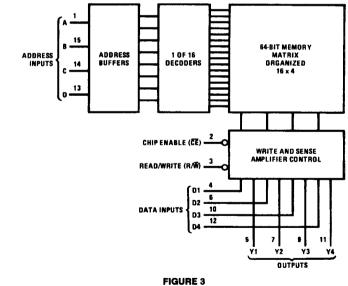
Note 1: Waveform 1 is for the output with internal conditions such that the output is low except when disabled.

Note 2: When measuring delay times from address inputs, the chip-enable input is low and the read/write input is high.

Note 3: When measuring delay times from chip-enable input, the address inputs are steady-state and the read/write input is high.

Note 4: input waveforms are supplied by pulse generators having the following characteristics: $t_{f} \le 2.5$ ns, $t_{f} \le 2.5$ ns, PRR ≤ 1 MHz and $Z_{OUT} \approx 50\Omega$.

Block Diagram



TL/L/9231-8

AC Test Circuits DM75S06/DM85S06 Vcc FROM OUTPUT UNDER TEST TL/L/9231-9 DM75S07(A)/DM85S07(A) TEST POINT FROM OUTPUT UNDER TEST TL/L/9231-10 C_L includes probe and jig capacitance. All diodes are 1N3064. FIGURE 4